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# PATENT ABSTRACTS OF JAPAN

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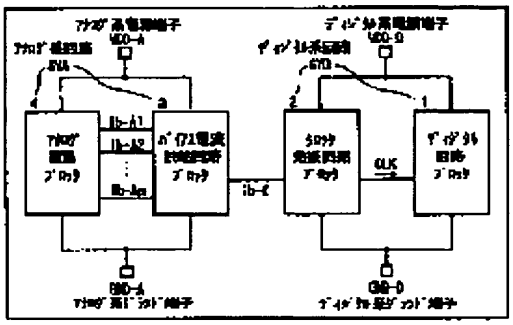
(71)Applicant : FUJI ELECTRIC CO LTD
(72)Inventor : YOSHIDA YUTAKA

## (54) SEMICONDUCTOR INTEGRATED CIRCUIT

(57)Abstract:
PROBLEM TO BE SOLVED: To suppress the effect of noises on an analog circuit, and to measure even the leakage current of a circuit which consumes current under a steady state without increasing the number of terminals, in an IC with a digital circuit block, a clock oscillation block, a bias current-supply circuit block, an analog circuit block or the like.
SOLUTION: Well regions on an IC substrate of a digital circuit SYD such as blocks 1, 2 as noise sources and an analog circuit SYA such as blocks 4, 3 suscetible to noises are divided, and the power supplies and ground terminals of both systems are separated and both systems are separated in noises. A current is determined by supplying the blocks 2, 4, by which the current is made to flow under a steady state, with a bias current from the block 3. When potential difference among an analog power supply and ground terminals VDD-A, GND-A is eliminated, the supply of the bias current to the block 2 is stopped and the current of the block 2 reaches zero, and leakage currents in the digital power supply and ground terminals VDD-D, GND-D are measured.



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